## School on Synchrotron and Free-Electron-Laser Based Methods: Multidisciplinary Applications and Perspectives | (smr 2812)

Contribution ID: 119 Type: not specified

## High-resolution X-Ray Emission spectroscopy and XAFS: applications using calibrated instrumentation

Thursday, 7 April 2016 17:15 (1:00)

Content

Summary

 $\begin{tabular}{ll} \textbf{Presenter(s)}: & BURKHARD \ BECKHOFF \ (PTB\text{-}Berlin, \ Germany) \\ \end{tabular}$ 

Session Classification: not yet classified